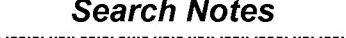


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/522,771	FUJIHARA ET AL.	
	Examiner	Art Unit	
	CYNTHIA LEE	1795	

Search Notes



Application/Control No.

10/522,771

Examiner

CYNTHIA LEE

**Applicant(s)/Patent under
Reexamination**

FUJIHARA ET AL.

Art Unit

1795

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner